

# EUROPEAN PATENT OFFICE

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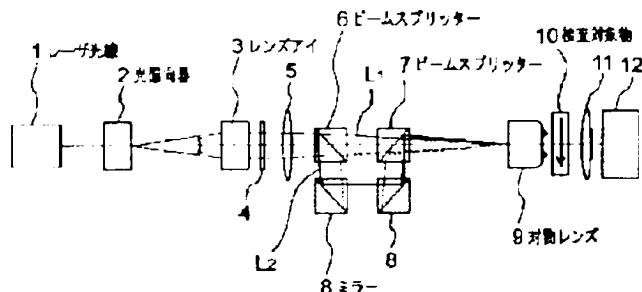
APPLICATION NUMBER 10232698

APPLICANT NEC CORP;

INVENTOR YANO JUNICHI;

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TITLE RETICLE INSPECTION APPARATUS



ABSTRACT PROBLEM TO BE SOLVED: To simplify apparatus constitution by decreasing the number of acousto-optic elements to be used.

SOLUTION: The laser beam emitted from a laser beam source 1 is deflected with lapse of time by an optical deflector 2 and the beam is made incident on a lens array 3 by which the scanning inspection light rays of plural condensing spots are formed. Next, these scanning inspection light rays are relayed via a relay lens 5 to an objective lens 9. A beam splitter 6 is arranged in mid-way of the relaying to divide the scanning inspection light rays L1, L2 of the condensing spots. The reflected scanning inspection light ray L2 is reflected by the beam splitter 7 and is cast to an object 10 to be inspected by regulating a mirror 8 so as to have an angle with the scanning inspection light ray L1 transmitted at the time of making the light incident on the objective lens 9. At this time, the respective light rays L1, L2 are provided with the angle with the objective lens 9, by which the inspection of the positions of the two points is simultaneously executed.

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